

Measurement Conditions

DASY system configuration, as far as not given on page 1.

	V. A	
DASY Version	DASY52	V52.10.4
Extrapolation	Advanced Extrapolation	
Phantom	Modular Flat Phantom	
Distance Dipole Center - TSL	10 mm	with Spacer
Zoom Scan Resolution	dx, dy, dz = 5 mm	
Frequency	2450 MHz ± 1 MHz	

Head TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	39.2	1.80 mho/m
Measured Head TSL parameters	(22.0 ± 0.2) °C	38.3 ± 6 %	1.85 mho/m ± 6 %
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR measured	250 mW input power	13.4 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	52.6 W/kg ± 17.0 % (k=2)
SAR averaged over 10 cm3 (10 c) of Head TPI	aandition	× 100 0 0
SAR averaged over 10 cm ³ (10 g) of Head TSL	condition	6 21 W/ka

Body TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Body TSL parameters	22.0 °C	52.7	1.95 mho/m
Measured Body TSL parameters	(22.0 ± 0.2) °C	53.0 ± 6 %	2.01 mho/m ± 6 %
Body TSL temperature change during test	< 0.5 °C		

SAR result with Body TSL

SAR averaged over 1 cm ³ (1 g) of Body TSL	Condition	
SAR measured	250 mW input power	12.5 W/kg
SAR for nominal Body TSL parameters	normalized to 1W	49.3 W/kg ± 17.0 % (k=2)

SAR averaged over 10 cm ³ (10 g) of Body TSL	condition	
SAR measured	250 mW input power	5.93 W/kg
SAR for nominal Body TSL parameters	normalized to 1W	23.6 W/kg ± 16.5 % (k=2)

Certificate No: D2450V2-715_Dec23



Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters with Head TSL

Impedance, transformed to feed point	51.7 Ω + 2.1 jΩ
Return Loss	- 31.6 dB

Antenna Parameters with Body TSL

Impedance, transformed to feed point	49.4 Ω + 2.5 jΩ
Return Loss	- 31.8 dB

General Antenna Parameters and Design

Electrical Delay (one direction)	1 157 pc
Electrical Bendy (ene direction)	1.10/110

After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard.

No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by	SPEAG	

Certificate No: D2450V2-715_Dec23

Page 4 of 8



DASY5 Validation Report for Head TSL

Date: 07.12.2023

Test Laboratory: SPEAG, Zurich, Switzerland

DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN:715

Communication System: UID 0 - CW; Frequency: 2450 MHz Medium parameters used: f = 2450 MHz; σ = 1.85 S/m; ϵ_r = 38.3; ρ = 1000 kg/m³ Phantom section: Flat Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EX3DV4 SN7349; ConvF(7.96, 7.96, 7.96) @ 2450 MHz; Calibrated: 03.11.2023
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn601; Calibrated: 03.10.2023
- Phantom: Flat Phantom 5.0 (front); Type: QD000P50AA; Serial: 1001
- DASY52 52.10.4(1535); SEMCAD X 14.6.14(7501)

Dipole Calibration for Head Tissue/Pin=250 mW, d=10mm/Zoom Scan (7x7x7)/Cube 0:

Measurement grid: dx=5mm, dy=5mm, dz=5mm Reference Value = 116.1 V/m; Power Drift = 0.03 dB Peak SAR (extrapolated) = 26.5 W/kg SAR(1 g) = 13.4 W/kg; SAR(10 g) = 6.21 W/kg Smallest distance from peaks to all points 3 dB below = 9 mm Ratio of SAR at M2 to SAR at M1 = 50.6% Maximum value of SAR (measured) = 21.9 W/kg



0 dB = 21.9 W/kg = 13.40 dBW/kg

Certificate No: D2450V2-715_Dec23

Page 5 of 8



Impedance Measurement Plot for Head TSL



Certificate No: D2450V2-715_Dec23

Page 6 of 8



DASY5 Validation Report for Body TSL

Date: 06.12.2023

Test Laboratory: SPEAG, Zurich, Switzerland

DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN:715

Communication System: UID 0 - CW; Frequency: 2450 MHz Medium parameters used: f = 2450 MHz; $\sigma = 2.01$ S/m; $\epsilon_r = 53$; $\rho = 1000$ kg/m³ Phantom section: Flat Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EX3DV4 SN7349; ConvF(8.12, 8.12, 8.12) @ 2450 MHz; Calibrated: 03.11.2023
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn601; Calibrated: 03.10.2023
- Phantom: Flat Phantom 5.0 (back); Type: QD 000 P50 AA; Serial: 1002
- DASY52 52.10.4(1535); SEMCAD X 14.6.14(7501)

Dipole Calibration for Body Tissue/Pin=250 mW, d=10mm/Zoom Scan (7x7x7)/Cube 0:

Measurement grid: dx=5mm, dy=5mm, dz=5mm Reference Value = 107.3 V/m; Power Drift = 0.08 dB Peak SAR (extrapolated) = 23.3 W/kg SAR(1 g) = 12.5 W/kg; SAR(10 g) = 5.93 W/kg Smallest distance from peaks to all points 3 dB below = 8.9 mm Ratio of SAR at M2 to SAR at M1 = 54.6% Maximum value of SAR (measured) = 20.0 W/kg



0 dB = 20.0 W/kg = 13.01 dBW/kg

Certificate No: D2450V2-715_Dec23

Page 7 of 8



Impedance Measurement Plot for Body TSL



Certificate No: D2450V2-715_Dec23

Page 8 of 8

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Accredited by the Swiss Accreditation Service (SAS)



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Swiss Calibration Service

Accreditation No.: SCS 0108

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The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates **TüV SÜD** Certificate No. D6.5GHzV2-1071 Jul24 Client Fareham, United Kingdom **CALIBRATION CERTIFICATE** Object D6.5GHzV2 - SN:1071 Calibration procedure(s) QA CAL-22.v7 Calibration Procedure for SAR Validation Sources between 3-10 GHz July 04, 2024 Calibration date: This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) Primary Standards ID # Cal Date (Certificate No.) Scheduled Calibration Power sensor R&S NRP33T SN: 100967 28-Mar-24 (No. 217-04038) Mar-25 Reference 20 dB Attenuator SN: BH9394 (20k) 26-Mar-24 (No. 217-04046) Mar-25 Mismatch combination SN: 84224 / 360D 28-Mar-24 (No. 217-04050) Mar-25 SN: 7405 Reference Probe EX3DV4 01-Jul-24 (No. EX3-7405_Jul24) Jul-25 DAE4 SN: 908 27-Mar-24 (No. DAE4-908_Mar24) Mar-25 Secondary Standards ID# Check Date (in house) Scheduled Check RF generator Anapico APSIN20G SN: 827 18-Dec-18 (in house check Jan-24) In house check: Jan-25 Power sensor NRP-723 SN: 100169 10-Jan-19 (in house check Jan-24) In house check: Jan-25 Power sensor NRP-18T SN: 100950 28-Sep-22 (in house check Jan-24) In house check: Jan-25 Network Analyzer Keysight E5063A SN:MY54504221 31-Oct-19 (in house check Oct-22) In house check: Oct-25 Name Function Signature Calibrated by: Aldonia Georgiadou Laboratory Technician Approved by: Sven Köhn Technical Manager Issued: July 8, 2024 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: D6.5GHzV2-1071_Jul24

Page 1 of 6



Calibration Laboratory of Schmid & Partner **Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland



Schweizerischer Kalibrierdienst S Service suisse d'étalonnage C Servizio svizzero di taratura S **Swiss Calibration Service**

Accreditation No.: SCS 0108

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Glossary:

TSL	tissue simulating liquid
ConvF	sensitivity in TSL / NORM x,y,z
N/A	not applicable or not measured

Calibration is Performed According to the Following Standards:

a) IEC/IEEE 62209-1528, "Measurement Procedure For The Assessment Of Specific Absorption Rate Of Human Exposure To Radio Frequency Fields From Hand-Held And Body-Worn Wireless Communication Devices - Part 1528: Human Models, Instrumentation And Procedures (Frequency Range Of 4 MHz To 10 GHz)", October 2020.

Additional Documentation:

b) DASY System Handbook

Methods Applied and Interpretation of Parameters:

- Measurement Conditions: Further details are available from the Validation Report at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- Antenna Parameters with TSL: The dipole is mounted with the spacer to position its feed point exactly below the center marking of the flat phantom section, with the arms oriented parallel to the body axis.
- Feed Point Impedance and Return Loss: These parameters are measured with the dipole positioned under the liquid filled phantom. The Return Loss ensures low reflected power. No uncertainty required.
- SAR measured: SAR measured at the stated antenna input power.
- SAR normalized: SAR as measured, normalized to an input power of 1 W at the antenna connector.
- SAR for nominal TSL parameters: The measured TSL parameters are used to calculate the nominal SAR result.
- The absorbed power density (APD): The absorbed power density is evaluated according to Samaras T, Christ A, Kuster N, "Compliance assessment of the epithelial or absorbed power density . above 6 GHz using SAR measurement systems", Bioelectromagnetics, 2021 (submitted). The additional evaluation uncertainty of 0.55 dB (rectangular distribution) is considered.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: D6.5GHzV2-1071_Jul24

Page 2 of 6



Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY6	V16.2
Extrapolation	Advanced Extrapolation	
Phantom	Modular Flat Phantom	
Distance Dipole Center - TSL	5 mm	with Spacer
Zoom Scan Resolution	dx, dy = 3.4 mm, dz = 1.4 mm	Graded Ratio = 1.4 (Z direction)
Frequency	6500 MHz ± 1 MHz	

Head TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	34.5	6.07 mho/m
Measured Head TSL parameters	(22.0 ± 0.2) °C	35.8 ± 6 %	6.26 mho/m ± 6 %
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR measured	100 mW input power	29.5 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	297 W/kg ± 24.7 % (k=2)
		2008 3007 Mar Martine act Mar 54 - 545
SAR averaged over 8 cm ³ (8 g) of Head TSL	Condition	
SAR measured	100 mW input power	6.57 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	66.3 W/kg ± 24.4 % (k=2)
SAR averaged over 10 cm ³ (10 g) of Head TSL	condition	
SAR measured	100 mW input power	5.37 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	54.2 W/kg ± 24.4 % (k=2)

Certificate No: D6.5GHzV2-1071_Jul24

Page 3 of 6



Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters with Head TSL

Impedance, transformed to feed point	49.5 Ω - 1.1 jΩ		
Return Loss	- 38.4 dB		

APD (Absorbed Power Density)

APD averaged over 1 cm ²	Condition		
APD measured	100 mW input power	297 W/m ²	
APD measured	normalized to 1W	2970 W/m² ± 29.2 % (k=2)	
ADD assessed assess 4 arm ²	nondilion		
APD averaged over 4 cm-	condition		
APD measured	100 mW input power	131 W/m ²	

normalized to 1W

1310 W/m² ± 28.9 % (k=2)

APD measured

*The reported APD values have been derived using the psSAR1g and psSAR8g.

General Antenna Parameters and Design

After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard.

No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by	SPEAG

Certificate No: D6.5GHzV2-1071_Jul24

Page 4 of 6



DASY6 Validation Report for Head TSL

Measurement Report for D6.5GHz-1071, UID 0 -, Channel 6500 (6500.0MHz)

Device under 1	Fest Properties						
Name, Manufa	acturer Di	imensions	MI [mm]	E	DUT Type	e	
D6.5GHz	1	6.0 x 6.0 x	300.0 SN	: 1071			
Exposure Conc	litions						
Phantom	Position, Test	Band	Group,	Frequency	Conversion	TSL Cond.	T5L
Section, TSL	Distance [mm]		UID	[MHz]	Factor	[S/m]	Permittivity
Flat, HSL	5.00	Band	CW,	6500	5.42	6.26	35.8
Hardware Seti Phantom	цр T	SL		Probe, Calil	bration Date	DAE, Calib	ration Date
MFP V8.0 Cent	ter - 1182 H	IBBL600-10	000V6	EX3DV4 - SI	N7405, 2024-07-01	DAE4 Sn90	08, 2024-03-27
Scan Setup				Measureme	ent Results		
			Zoom Scan				Zoom Scan
Grid Extents	[mm]		22.0 x 22.0 x 22.0	Date		2	024-07-04, 13:30
Grid Steps [m	nm]		3.4 x 3.4 x 1.4	psSAR1g [W/Kg]		29.5
Sensor Surfac	:e [mm]		1.4	psSAR8g [W/Kg]		6.57
Graded Grid			Yes	psSAR10g	[W/Kg]		5.37
Grading Ratio	2		1.4	Power Dri	ft [dB]		0.03
MAIA			N/A	Power Sca	ling		Disabled
Surface Dete	ction		VMS + 6p	Scaling Fa	ctor (dB)		
Scan Method			Measured	TSL Correc	tion		No correction
				M2/M1 (9	6]		54.3
				Dist 3dB P	eak [mm]		4.8



Certificate No: D6.5GHzV2-1071_Jul24

Page 5 of 6



Impedance Measurement Plot for Head TSL



Certificate No: D6.5GHzV2-1071_Jul24

Page 6 of 6



ANNEX C

TEST RESULTS



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2480.0, 78	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]		3.0	1.4
Graded Grid		n/a	Yes
Grading Ratio		n/a	1.5
MAIA		N/A	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scar	Zoom Scan
Date		2024-10-29, 20:46	2024-10-29, 20:53
psSAR1g [W/Kg]		0.245	0.263
psSAR10g [W/Kg]		0.117	0.118
Power Drift [dB]		0.18	0.17
Power Scaling	Disabled		Disabled
Scaling Factor [dB]			
TSL Correction	Positive only		Positive only
M2/M1 [%]			75.8
Dist 3dB Peak [mm]			8.0





Figure C1: SAR Testing Results for the A3241 at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2480.0, 78	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

		Area Scan	Zoom Scan			
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0			
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5			
Sensor Surface [mm]		3.0	1.4			
Graded Grid		n/a	Yes			
Grading Ratio		n/a	1.5			
MAIA		N/A	N/A			
Surface Detection		VMS + 6p	VMS + 6p			
Scan Method		Measured	Measured			
Measurement Results						
		Area Scar	Zoom Scan			
Date		2024-10-29, 22:13	3 2024-10-29, 22:21			
psSAR1g [W/Kg]		0.212	0.238			
psSAR10g [W/Kg]		0.103	0.107			
Power Drift [dB]		0.19	0.09			
Power Scaling	Disabled		Disabled			
Scaling Factor [dB]						
TSL Correction		Positive only	Positive only			
M2/M1 [%]			75.2			
Dist 3dB Peak [mm]			7.7			





Figure C2: SAR Testing Results for A3241 the at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2480.0, 78	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

		Area Scan	Zoom Scan			
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0			
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5			
Sensor Surface [mm]		3.0	1.4			
Graded Grid		n/a	Yes			
Grading Ratio		n/a	1.5			
MAIA		N/A	N/A			
Surface Detection		VMS + 6p	VMS + 6p			
Scan Method		Measured	Measured			
Measurement Results						
		Area Scar	Zoom Scan			
Date		2024-10-29, 20:46	2024-10-29, 20:53			
psSAR1g [W/Kg]		0.245	0.263			
psSAR10g [W/Kg]		0.117	0.118			
Power Drift [dB]		0.18	0.17			
Power Scaling	Disabled		Disabled			
Scaling Factor [dB]						
TSL Correction		Positive only	Positive only			
M2/M1 [%]			75.8			
Dist 3dB Peak [mm]			8.0			





Figure C3: SAR Testing Results for the A3241 at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2480.0, 78	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

		Area Scan	Zoom Scan			
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0			
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5			
Sensor Surface [mm]		3.0	1.4			
Graded Grid		n/a	Yes			
Grading Ratio		n/a	1.5			
MAIA		N/A	N/A			
Surface Detection		VMS + 6p	VMS + 6p			
Scan Method		Measured	Measured			
Measurement Results						
		Area Scar	Zoom Scan			
Date		2024-10-29, 22:13	2024-10-29, 22:21			
psSAR1g [W/Kg]		0.212	0.238			
psSAR10g [W/Kg]		0.103	0.107			
Power Drift [dB]		0.19	0.09			
Power Scaling	Disabled		Disabled			
Scaling Factor [dB]						
TSL Correction		Positive only	Positive only			
M2/M1 [%]			75.2			
Dist 3dB Peak [mm]			7.7			





Figure C4: SAR Testing Results for the A3241 at 2480 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5250000 (5250.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.000, 5250000	5.18	4.50	34.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-10-28	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Sca	in Zoom Scan
Date	2024-10-30, 02:0	2024-10-30, 02:16
psSAR1g [W/Kg]	0.13	0.136
psSAR10g [W/Kg]	0.05	.0.040
Power Drift [dB]	0.1	7 -0.13
Power Scaling	Disable	Disabled
Scaling Factor [dB]		
TSL Correction	Positive or	ly Positive only
M2/M1 [%]		57.7
Dist 3dB Peak [mm]		7.6





Figure C5: SAR Testing Results for the A3241 at 5250 MHz



Measurement Report for BB2403, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5150000 (5150.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BB2403,	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5150.000, 5150000	5.18	4.39	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5 B5.prn, 2024-10-28	EX3DV4 - SN7805, 2024-02-	DAE4ip Sn1785, 2024-02-
2202		14	13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-10-30, 02:29	2024-10-30, 02:37
psSAR1g [W/Kg]	0.175	0.185
psSAR10g [W/Kg]	0.067	0.062
Power Drift [dB]	0.18	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		61.9
Dist 3dB Peak [mm]		8.1





Figure C6: SAR Testing Results for the A3241 at 5150 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5850000 (5850.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.000, 5850000	4.63	5.16	33.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-10-28	02-14	02-13

		Area Scan	Zoom Scan				
Grid Extents [mm]		140.0 x 200.0	22.0 x 22.0 x 22.0				
Grid Steps [mm]		10.0 x 10.0	4.0 x 4.0 x 1.4				
Sensor Surface [mm]		3.0	1.4				
Graded Grid		N/A	Yes				
Grading Ratio		N/A	1.4				
MAIA		Y	Y				
Surface Detection		VMS + 6p	VMS + 6p				
Scan Method		Measured	Measured				
Measurement Results	Measurement Results						
		Area Scar	Zoom Scan				
Date		2024-10-30, 04:11	2024-10-30, 04:18				
psSAR1g [W/Kg]		0.318	3 0.352				
psSAR10g [W/Kg]		0.111	0.107				
Power Drift [dB]		0.16	0.00				
Power Scaling		Disabled	Disabled				
Scaling Factor [dB]							
TSL Correction		Positive only	Positive only				
M2/M1 [%]			57.4				
Dist 3dB Peak [mm]			7.9				





Figure C7: SAR Testing Results for the A3241 at 5850 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5788000 (5788.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5788.000, 5788000	4.63	5.09	34.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-10-28	02-14	02-13

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]		10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0	1.4
Graded Grid		N/A	Yes
Grading Ratio		N/A	1.4
MAIA		Y	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scan	Zoom Scan
Date		2024-10-30, 07:19	2024-10-30, 07:31
psSAR1g [W/Kg]		0.358	0.414
psSAR10g [W/Kg]		0.123	0.126
Power Drift [dB]		-0.16	-0.29
Power Scaling		Disabled	Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			56.8
Dist 3dB Peak [mm]			7.2





Figure C8: SAR Testing Results for the A3241 at 5788 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5250000 (5250.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.000, 5250000	5.18	4.50	34.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-10-28	02-14	02-13

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]		10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0	1.4
Graded Grid		N/A	Yes
Grading Ratio		N/A	1.4
MAIA		Y	Y
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scar	Zoom Scan
Date		2024-10-30, 02:07	2024-10-30, 02:16
psSAR1g [W/Kg]		0.130	0.136
psSAR10g [W/Kg]		0.052	0.040
Power Drift [dB]		0.17	-0.13
Power Scaling		Disablec	Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			57.7
Dist 3dB Peak [mm]			7.6





Figure C9: SAR Testing Results for the A3241 at 5250 MHz



Measurement Report for BB2403, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5150000 (5150.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BB2403,	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5150.000, 5150000	5.18	4.39	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.58 deg.C 2024-Oct-28 SYS5 B5.prn, 2024-10-28	EX3DV4 - SN7805, 2024-02-	DAE4ip Sn1785, 2024-02-
2202		14	13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-10-30, 02:29	2024-10-30, 02:37
psSAR1g [W/Kg]	0.175	0.185
psSAR10g [W/Kg]	0.067	0.062
Power Drift [dB]	0.18	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		61.9
Dist 3dB Peak [mm]		8.1





Figure C10: SAR Testing Results for the A3241 at 5150 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5850000 (5850.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.000, 5850000	4.63	5.12	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.23 deg.C 2024-Oct-30 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5, 2024-10-30	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		
	Area Sca	n Zoom Scan
Date	2024-10-30, 11:5	4 2024-10-30, 12:01
psSAR1g [W/Kg]	0.13	1 0.154
psSAR10g [W/Kg]	0.04	4 0.038
Power Drift [dB]	-0.2	1 -0.17
Power Scaling	Disable	d Disabled
Scaling Factor [dB]		
TSL Correction	Positive on	Positive only
M2/M1 [%]		56.8
Dist 3dB Peak [mm]		5.6





Figure C11: SAR Testing Results for the A3241 at 5850.0 MHz



Measurement Report for A3241, BACK, Custom Band, IEEE 802.15.1 Bluetooth (GFSK, DH5), Channel 5850000 (5850.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.000, 5850000	4.63	5.12	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 21.23 deg.C 2024-Oct-30 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5, 2024-10-30	02-14	02-13

	Area Sca	Zoom Scan
Grid Extents [mm]	140.0 x 200.	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.	1.4
Graded Grid	N/	Yes
Grading Ratio	N/	1.4
MAIA		Y
Surface Detection	VMS + 6	VMS + 6p
Scan Method	Measure	d Measured
Measurement Results		
	Area S	zan Zoom Scan
Date	2024-10-30, 13	2024-10-30, 14:07
psSAR1g [W/Kg]	0.1	38 0.155
psSAR10g [W/Kg]	0.0	0.043
Power Drift [dB]	0	-0.12
Power Scaling	Disab	led Disabled
Scaling Factor [dB]		
TSL Correction	Positive of	nly Positive only
M2/M1 [%]		57.8
Dist 3dB Peak [mm]		7.2




Figure C12: SAR Testing Results for the A3241 at 5850.0 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section,	Position, Test Distance	Band	Group,	Frequency [MHz], Channel	Conversion	TSL Conductivity	TSL
TSL	[mm]		UID	Number	Factor	[S/m]	Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2480.0, 2480000	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Sca	n Zoom Scan
Date	2024-10-30, 01:3	7 2024-10-30, 01:44
psSAR1g [W/Kg]	0.96	5 1.03
psSAR10g [W/Kg]	0.47	0 0.470
Power Drift [dB]	-0.0	0 -0.00
Power Scaling	Disable	d Disabled
Scaling Factor [dB]		
TSL Correction	Positive on	y Positive only
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		8.0





Figure C13: SAR Testing Results for the A3241 at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section,	Position, Test Distance	Band	Group,	Frequency [MHz], Channel	Conversion	TSL Conductivity	TSL
TSL	[mm]		UID	Number	Factor	[S/m]	Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2480.0, 2480000	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		
	Area Scar	Zoom Scan
Date	2024-10-30, 02:31	2024-10-30, 02:38
psSAR1g [W/Kg]	0.897	0.936
psSAR10g [W/Kg]	0.429	0.426
Power Drift [dB]	-0.01	0.02
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.9
Dist 3dB Peak [mm]		7.1





Figure C14: SAR Testing Results for the A3241 at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section,	Position, Test Distance	Band	Group,	Frequency [MHz], Channel	Conversion	TSL Conductivity	TSL
TSL	[mm]		UID	Number	Factor	[S/m]	Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2480.0, 2480000	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		
	Area Scar	Zoom Scan
Date	2024-10-30, 03:28	3 2024-10-30, 03:35
psSAR1g [W/Kg]	0.323	0.343
psSAR10g [W/Kg]	0.157	0.155
Power Drift [dB]	0.02	0.00
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	 Positive only	Positive only
M2/M1 [%]		74.6
Dist 3dB Peak [mm]		8.0





Figure C15: SAR Testing Results for the A3241 at 2480 MHz



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section,	Position, Test Distance	Band	Group,	Frequency [MHz], Channel	Conversion	TSL Conductivity	TSL
TSL	[mm]		UID	Number	Factor	[S/m]	Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2480.0, 2480000	7.41	1.86	40.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head 20.3 deg.C 2024-Oct-28 SYS6 B6.prn, 2024-Oct-29	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203		05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		1
	Area Scar	Zoom Scan
Date	2024-10-30, 04:38	3 2024-10-30, 04:45
psSAR1g [W/Kg]	0.301	0.315
psSAR10g [W/Kg]	0.143	0.142
Power Drift [dB]	-0.01	-0.04
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.5
Dist 3dB Peak [mm]		7.0





Figure C16: SAR Testing Results for the A3241 at 2480 MH



Measurement Report for A3241, BACK, WLAN 2.4GHz, IEEE 802.11b WiFi 2.4 GHz (DSSS, 1 Mbps, 99pc duty cycle), Channel 11 (2462.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10415- AAA	2462.0, 11	7.41	1.84	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Scar	Zoom Scan
Date	2024-11-11, 13:30	2024-11-11, 13:38
psSAR1g [W/Kg]	0.684	0.719
psSAR10g [W/Kg]	0.312	0.322
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		76.9
Dist 3dB Peak [mm]		9.0





Figure C17: SAR Testing Results for the A3241 at 2462 MHz



Measurement Report for A3241, BACK, WLAN 2.4GHz, IEEE 802.11b WiFi 2.4 GHz (DSSS, 1 Mbps, 99pc duty cycle), Channel 11 (2462.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10415- AAA	2462.0, 11	7.41	1.84	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Scar	Zoom Scan
Date	2024-11-11, 15:15	5 2024-11-11, 15:22
psSAR1g [W/Kg]	0.686	0.744
psSAR10g [W/Kg]	0.324	0.335
Power Drift [dB]	0.01	0.01
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.5
Dist 3dB Peak [mm]		7.7





Figure C18: SAR Testing Results for the A3241 at 2462 MHz



Measurement Report for A3241, BACK, WLAN 2.4GHz, IEEE 802.11g WiFi 2.4 GHz (ERP-OFDM, 6 Mbps, 99pc duty cycle), Channel 10 (2457.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10416- AAA	2457.0, 10	7.41	1.84	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]		3.0	1.4
Graded Grid		n/a	Yes
Grading Ratio		n/a	1.5
маја		N/A	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scar	Zoom Scan
Date		2024-11-11, 17:14	L 2024-11-11, 17:22
psSAR1g [W/Kg]		0.602	2 0.646
psSAR10g [W/Kg]		0.289	0.289
Power Drift [dB]	-0.00		-0.03
Power Scaling		Disabled	Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			74.9
Dist 3dB Peak [mm]			7.0





Figure C19: SAR Testing Results for the A3241 at 2457 MHz



Measurement Report for A3241, BACK, WLAN 2.4GHz, IEEE 802.11g WiFi 2.4 GHz (ERP-OFDM, 6 Mbps, 99pc duty cycle), Channel 10 (2457.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10416- AAA	2457.0, 10	7.41	1.84	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]		10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]		3.0	1.4
Graded Grid		n/a	Yes
Grading Ratio		n/a	1.5
МАІА		N/A	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scar	Zoom Scan
Date		2024-11-11, 18:09	2024-11-11, 18:17
psSAR1g [W/Kg]		0.683	0.720
psSAR10g [W/Kg]		0.312	0.324
Power Drift [dB]		0.01	0.01
Power Scaling		Disablec	Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			76.3
Dist 3dB Peak [mm]			8.0





Figure C20: SAR Testing Results for the A3241 at 2457 MHz



Measurement Report for A3241, BACK, WLAN 2.4GHz, IEEE 802.11n (HT Greenfield, 6.5 Mbps, BPSK), Channel 10 (2457.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10193- CAD	, 10	7.41	1.84	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan		Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0		30.0 x 30.0 x 30.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0		5.0 x 5.0 x 1.5	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0		1.4	1.4
Graded Grid	n/a		Yes	Yes
Grading Ratio	n/a		1.5	1.5
MAIA	N/A		N/A	N/A
Surface Detection	VMS + 6p		VMS + 6p	VMS + 6p
Scan Method	Measured	Measured		Measured
Measurement Results				
	Area S	Scan	Zoom Scar	Zoom Scan
Date	2024-11-11, 1	9:30	2024-11-11, 19:38	2024-11-11, 19:45
psSAR1g [W/Kg]	0	.700	0.730	0.662
psSAR10g [W/Kg]	0	.323	0.328	0.296
Power Drift [dB]	-	0.01	-0.03	-0.02
Power Scaling	Disa	bled	Disabled	Disabled
Scaling Factor [dB]				
TSL Correction	Positive	only	Positive only	Positive only
M2/M1 [%]			75.5	5 74.6
Dist 3dB Peak [mm]			7.7	7.0





Figure C21: SAR Testing Results for the A3241 at 2457 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11a/h WiFi 5 GHz (OFDM, 6 Mbps, 99pc duty cycle), Channel 40 (5200.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10417- AAD	5200.000, 40	5.18	4.57	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Scar	Zoom Scan
Date	2024-11-12, 14:01	2024-11-12, 14:09
psSAR1g [W/Kg]	0.627	0.662
psSAR10g [W/Kg]	0.240	0.247
Power Drift [dB]	0.05	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		8.4





Figure C22: SAR Testing Results for the A3241 at 5200 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11a/h WiFi 5 GHz (OFDM, 6 Mbps, 99pc duty cycle), Channel 36 (5180.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10417- AAD	5180.000, 36	5.18	4.54	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		-
	Area Scar	Zoom Scan
Date	2024-11-12, 15:12	2 2024-11-12, 15:20
psSAR1g [W/Kg]	0.696	0.719
psSAR10g [W/Kg]	0.266	0.261
Power Drift [dB]	0.02	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		8.7





Figure C23: SAR Testing Results for the A3241 at 5180 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11n (HT Greenfield, 13.5 Mbps, BPSK), Channel 46 (5230.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10114- CAE	5230.000, 46	5.18	4.60	35.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

		Area Scan		Zoom Scan	Zoom Scan
Grid Extents [mm]		x 260.0		22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]		10.0 x 10.0		4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0		1.4	1.4
Graded Grid		N/A		Yes	Yes
Grading Ratio		N/A		1.4	1.4
MAIA		Y		N/A	N/A
Surface Detection		VMS + 6p		VMS + 6p	VMS + 6p
Scan Method		Measured		Measured	Measured
Measurement Results	1				
		Area Se	can	Zoom Sca	in Zoom Scan
Date		2024-11-12, 18	3:23	2024-11-12, 18:3	2024-11-12, 18:47
psSAR1g [W/Kg]		0.6	635	0.65	0.675
psSAR10g [W/Kg]		0.2	250	0.23	0.242
Power Drift [dB]		-0	0.02	0.0	-0.03
Power Scaling		Disabl		Disable	d Disabled
Scaling Factor [dB]					
TSL Correction		Positive of	only	Positive on	ly Positive only
M2/M1 [%]				61.	9 61.7
Dist 3dB Peak [mm]				8.	.7 8.2





Figure C24: SAR Testing Results for the A3241 at 5230 MHz



Measurement Report for A3241, BACK, U-NII-1, U-NII-2A, IEEE 802.11a/h WiFi 5 GHz (OFDM, 6 Mbps, 99pc duty cycle), Channel 64 (5320.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII-1, U- NII-2A	WLAN, 10417-AAD	5320.000, 64	5.01	4.70	35.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]		10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0	1.4
Graded Grid		N/A	Yes
Grading Ratio		N/A	1.4
MAIA		Y	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			
		Area Scar	Zoom Scan
Date		2024-11-13, 04:43	2024-11-13, 04:54
psSAR1g [W/Kg]		0.789	0.866
psSAR10g [W/Kg]		0.287	0.291
Power Drift [dB]		0.03	0.05
Power Scaling	Disabled		Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			62.2
Dist 3dB Peak [mm]			7.2





Figure C25: SAR Testing Results for the A3241 at 5230 MHz



Measurement Report for A3241, BACK, U-NII-1, U-NII-2A, IEEE 802.11a/h WiFi 5 GHz (OFDM, 6 Mbps, 99pc duty cycle), Channel 60 (5300.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII-1, U- NII-2A	WLAN, 10417-AAD	5300.000, 60	5.01	4.68	35.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan		Zoom Scan	Zoom Scan
Grid Extents [mm]	x 200.0		22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0		4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0		1.4	1.4
Graded Grid	N/A		Yes	Yes
Grading Ratio	N/A		1.4	1.4
MAIA	Y		Y	N/A
Surface Detection	VMS + 6p		VMS + 6p	VMS + 6p
Scan Method	Measured		Measured	
Measurement Results				
	Area Se	can	Zoom Sca	n Zoom Scan
Date	2024-11-13, 05	5:27	2024-11-13, 05:3	6 2024-11-13, 05:47
psSAR1g [W/Kg]	0.4	408	0.42	0.462
psSAR10g [W/Kg]	0.1	154	0.14	7 0.155
Power Drift [dB]	0	0.06	0.0	0 0.04
Power Scaling	Disab		Disable	d Disabled
Scaling Factor [dB]				
TSL Correction	Positive of	only	Positive on	ly Positive only
M2/M1 [%]			61.	2 60.0
Dist 3dB Peak [mm]			8.	0 6.9





Figure C26: SAR Testing Results for the A3241 at 5300 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11n (HT Mixed, 6.5 Mbps, BPSK), Channel 64 (5320.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10196- CAE	5320.000, 64	5.01	4.57	35.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 21.30 deg.C 2024-Nov-13 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-13	02-14	02-13

	Area Scan		Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	x 260.0		22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0		4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0		1.4	1.4
Graded Grid	N/A		Yes	Yes
Grading Ratio	N/A		1.4	1.4
MAIA	Y		N/A	N/A
Surface Detection	VMS + 6p		VMS + 6p	VMS + 6p
Scan Method	Measured	Measured		Measured
Measurement Results				-
	Area S	Scan	Zoom Sca	n Zoom Scan
Date	2024-11-14, 0	5:15	2024-11-14, 05:2	4 2024-11-14, 05:31
psSAR1g [W/Kg]	0	.604	0.66	5 0.469
psSAR10g [W/Kg]	0	.204	0.21	9 0.153
Power Drift [dB]		0.01	0.0	-0.02
Power Scaling	Disabled		Disable	d Disabled
Scaling Factor [dB]				
TSL Correction	Positive	only	Positive onl	Positive only
M2/M1 [%]			62.	60.2
Dist 3dB Peak [mm]			6.	4 6.6





Figure C27: SAR Testing Results for the A3241 at 5320 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 106 (5530.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5530.000, 106	4.75	4.94	34.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-11-11, 13:37	2024-11-11, 13:45
psSAR1g [W/Kg]	0.610	0.629
psSAR10g [W/Kg]	0.204	0.202
Power Drift [dB]	-0.16	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.2
Dist 3dB Peak [mm]		6.9





Figure C28: SAR Testing Results for the A3241 at 5530 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 122 (5610.000 MHz) Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5610.000, 122	4.56	5.03	34.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

		Area Scan	Zoom Scan
Grid Extents [mm]		140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	Grid Steps [mm]		4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0	1.4
Graded Grid		N/A	Yes
Grading Ratio		N/A	1.4
MAIA		Y	N/A
Surface Detection		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured
Measurement Results			-
		Area Scar	Zoom Scan
Date		2024-11-11, 15:43	2024-11-11, 15:55
psSAR1g [W/Kg]		0.613	0.644
psSAR10g [W/Kg]		0.213	0.207
Power Drift [dB]		-0.02	-0.06
Power Scaling		Disablec	Disabled
Scaling Factor [dB]			
TSL Correction		Positive only	Positive only
M2/M1 [%]			58.4
Dist 3dB Peak [mm]			7.2





Figure C29: SAR Testing Results for the A3241 at 5610 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 138 (5690.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5690.000, 138	4.56	5.12	34.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

		Area Scan		Zoom Scan	Zoom Scan
Grid Extents [mm]		x 260.0		22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]		10.0 x 10.0		4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]		3.0		1.4	1.4
Graded Grid		N/A		Yes	Yes
Grading Ratio		N/A		1.4	1.4
MAIA		Y		N/A	N/A
Surface Detection		VMS + 6p		VMS + 6p	VMS + 6p
Scan Method		Measured	Measured		Measured
Measurement Results					
	Area S		can	Zoom Sca	n Zoom Scan
Date	2024-11-12, 02		2:16	2024-11-12, 02:2	8 2024-11-12, 02:35
psSAR1g [W/Kg]	0.5		565	0.64	3 0.525
psSAR10g [W/Kg]	0.1		193	0.20	2 0.162
Power Drift [dB]	-0.0		0.02	0.0	2 0.03
Power Scaling	Disabl		bled	Disable	d Disabled
Scaling Factor [dB]					
TSL Correction	Positive o		only	Positive on	y Positive only
M2/M1 [%]				57.	9 58.7
Dist 3dB Peak [mm]				7.	2 7.2




Figure C30: SAR Testing Results for the A3241 at 5690 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5775.000, 155	4.63	5.21	34.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		
	Area Scar	Zoom Scan
Date	2024-11-12, 06:55	2024-11-12, 07:03
psSAR1g [W/Kg]	0.525	0.581
psSAR10g [W/Kg]	0.172	0.179
Power Drift [dB]	0.15	-0.02
Power Scaling	Disablec	Disabled
Scaling Factor [dB]		
TSL Correction	 Positive only	Positive only
M2/M1 [%]		58.7
Dist 3dB Peak [mm]		6.4





Figure C31: SAR Testing Results for the A3241 at 5775 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5775.000, 155	4.63	5.21	34.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured
Measurement Results		
	Area Scar	Zoom Scan
Date	2024-11-12, 07:18	3 2024-11-12, 07:29
psSAR1g [W/Kg]	0.64	0.708
psSAR10g [W/Kg]	0.210	0.224
Power Drift [dB]	0.11	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	/ Positive only
M2/M1 [%]		58.8
Dist 3dB Peak [mm]		6.4





Figure C32: SAR Testing Results for the A3241 at 5775 MHz



Measurement Report for A3241, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	WLAN 5GHz	WLAN, 10544- AAD	5775.000, 155	4.63	5.21	34.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.00 deg.C 2024-Nov-11 SYS5	EX3DV4 - SN7805, 2024-	DAE4ip Sn1785, 2024-
2202	B5.prn, 2024-11-11	02-14	02-13

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	N/A	Yes	Yes
Grading Ratio	N/A	1.4	1.4
MAIA	Y	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured
Measurement Results			
	Area S	can Zoom Sca	n Zoom Scan
Date	2024-11-12, 06	6:24 2024-11-12, 06:3	5 2024-11-12, 06:43
psSAR1g [W/Kg]	0.	610 0.66	7 0.573
psSAR10g [W/Kg]	0.	200 0.21	0 0.176
Power Drift [dB]	(-0.02	6 -0.05
Power Scaling	Disal	Disable	d Disabled
Scaling Factor [dB]			
TSL Correction	Positive	only Positive on	ly Positive only
M2/M1 [%]		58	3 58.2
Dist 3dB Peak [mm]		7	2 6.4





Figure C33: SAR Testing Results for the A3241 at 5775 MHz



Measurement Report for BB2403, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BB2403,	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755- AAC	6025.0, 15	5.61	5.45	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan		Zoom Scan
Grid Extents [mm]	153.0 x 204.0		22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5		3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0		1.4
Graded Grid	n/a		Yes
Grading Ratio	n/a		1.4
MAIA	Y		N/A
Surface Detection	VMS + 6p		VMS + 6p
Scan Method	Measured		Measured
Measurement Results			
	Are	a Scan	Zoom Scan
Date	2024-11-12	10:00	2024-11-12, 10:10
psSAR1g [W/Kg]		0.472	0.493
psSAR10g [W/Kg]		0.157	0.159
psAPD (4.0cm2, sq) [W/m2]			3.63
Power Drift [dB]		-0.02	-0.11
Power Scaling	Di	sabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positi	e only	Positive only
M2/M1 [%]			51.1
Dist 3dB Peak [mm]			7.5





Figure C34: SAR Testing Results for the A3241 at 6025 MHz



Measurement Report for A3241, BACK, U-NII-7, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 143 (6665.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 7	WLAN, 10755- AAC	6665.0, 143	5.61	6.20	32.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan	200m Scar
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	5 3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0) 1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	/ N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	J Measured
Measurement Results		
	Are	rea Scan Zoom Scar
Date	2024-11-12	2, 11:48 2024-11-12, 11:57
psSAR1g [W/Kg]		0.574 0.625
psSAR10g [W/Kg]		0.183 0.192
psAPD (4.0cm2, sq) [W/m2]		4.41
Power Drift [dB]		0.15 0.18
Power Scaling	D	Disabled Disabled
Scaling Factor [dB]		
TSL Correction	Positi	itive only Positive only
M2/M1 [%]		47.6
Dist 3dB Peak [mm]		7.5





Figure C35: SAR Testing Results for the A3241 at 6665 MHz



Measurement Report for A3241, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755- AAC	6025.0, 15	5.61	5.45	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan		Zoom Scan
Grid Extents [mm]	153.0 x 204.0	22.0 >	x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.	4 x 3.4 x 1.4
Sensor Surface [mm]	3.0		1.4
Graded Grid	n/a		Yes
Grading Ratio	n/a		1.4
MAIA	Y		N/A
Surface Detection	VMS + 6p		VMS + 6p
Scan Method	Measured		Measured
Measurement Results	1		
	Are	a Scan	Zoom Scan
Date	2024-11-12	14:56 2024-	11-12, 15:07
psSAR1g [W/Kg]		0.369	0.398
psSAR10g [W/Kg]		0.121	0.129
psAPD (4.0cm2, sq) [W/m2]			2.95
Power Drift [dB]		0.08	0.03
Power Scaling	Di	sabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positi	ve only	Positive only
M2/M1 [%]			52.3
Dist 3dB Peak [mm]			7.5





Figure C36: SAR Testing Results for the A3241 at 6025 MHz



Measurement Report for A3241, BACK, U-NII-7, IEEE 802.11ax (80MHz, MCS0, 99pc duty cycle), Channel 167 (6785.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 7	WLAN, 10731- AAC	6785.0, 167	5.61	6.34	32.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan	Zoo	om Scan
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.	.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3	3.4 x 1.4
Sensor Surface [mm]	3.0		1.4
Graded Grid	n/a		Yes
Grading Ratio	n/a		1.4
MAIA	Y		N/A
Surface Detection	VMS + 6p	V	MS + 6p
Scan Method	Measured	М	leasured
Measurement Results			
	Are	a Scan Zoo	om Scan
Date	2024-11-12	, 17:25 2024-11-1	2, 17:35
psSAR1g [W/Kg]		0.714	0.761
psSAR10g [W/Kg]		0.233	0.240
psAPD (4.0cm2, sq) [W/m2]			5.51
Power Drift [dB]		0.09	-0.01
Power Scaling	Di	sabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positiv	ve only Posi	tive only
M2/M1 [%]			48.1
Dist 3dB Peak [mm]			8.0





Figure C37: SAR Testing Results for the A3241 at 6785 MHz



Measurement Report for A3241, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755- AAC	, 15	5.61	5.45	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan		Zoom Scan	Zoom S	Scan
Grid Extents [mm]	x 272.0	22.0 x 22.0 x 22.0		22.0 x 22.0 x 2	22.0
Grid Steps [mm]	8.5 x 8.5		3.4 x 3.4 x 1.4	3.4 x 3.4 x	‹ 1.4
Sensor Surface [mm]	3.0		1.4		1.4
Graded Grid	n/a		Yes		Yes
Grading Ratio	n/a		1.4		1.4
MAIA	Y		N/A		N/A
Surface Detection	VMS + 6p		VMS + 6p	VMS -	+ 6p
Scan Method	Measured		Measured	Measu	ured
Measurement Results					
		Area Scan	Zoom	Scan Zoom S	Scan
Date	2024-1	1-12, 19:09	2024-11-12,	19:22 2024-11-12, 19	9:33
psSAR1g [W/kg]		0.402	(0.422 0.	.420
psSAR10g [W/kg]		0.134	(0.135 0.	.138
psAPD (4.0cm2, sq) [W/m2]				3.09	3.16
Power Drift [dB]		0.04		-0.01	0.02
Power Scaling		Disabled	Disa	abled Disal	bled
Scaling Factor [dB]					
TSL Correction	F	ositive only	Positive	e only Positive	only
M2/M1 [%]				51.8	52.4
Dist 3dB Peak [mm]				7.1	7.5





Figure C38: SAR Testing Results for the A3241 at 6025 MHz



Measurement Report for A3241, BACK, U-NII-7, IEEE 802.11ax (80MHz, MCS0, 99pc duty cycle), Channel 167 (6785.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	340.0 x 240.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 7	WLAN, 10731- AAC	, 167	5.61	6.34	32.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) -	HBBL-600-10000 DAK 3.5 Head ELI 20.40 deg.C 2024-Nov-11 SYS6	EX3DV4 - SN7809, 2024-	DAE4ip Sn1789, 2024-
2203	B6.prn, 2024-Nov-11	05-13	05-03

	Area Scan		Zoom Scan	Zoom Sca	
Grid Extents [mm]	x 272.0		22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.	
Grid Steps [mm]	8.5 x 8.5		3.4 x 3.4 x 1.4	3.4 x 3.4 x 1.	
Sensor Surface [mm]	3.0		1.4	1.	
Graded Grid	n/a		Yes	Ye	
Grading Ratio	n/a		1.4	1.	
MAIA	Y		N/A	N/	
Surface Detection	VMS + 6p		VMS + 6p	VMS + 6	
Scan Method	Measured		Measured	Measure	
Measurement Results					
		Area Scan	Zoom	Scan Zoom Sca	
Date	2024-1	1-12, 22:55	2024-11-12, 2	23:05 2024-11-12, 23:1	
psSAR1g [W/kg]		0.585	(0.621 0.45	
psSAR10g [W/kg]		0.192	(0.197 0.14	
psAPD (4.0cm2, sq) [W/m2]				4.52 3.2	
Power Drift [dB]		0.09		-0.02 0.0	
Power Scaling		Disabled	Disa	abled Disable	
Scaling Factor [dB]					
TSL Correction	F	ositive only	Positive	e only Positive on	
M2/M1 [%]				48.2 47	
Dist 3dB Peak [mm]				8.2 7.	





Figure C39: SAR Testing Results for the A3241 at 6785 MHz



Measurement Report for A3241, BACK, U-NII-7, IEEE 802.11ax (40MHz, MCS0, 99pc duty cycle), Channel 123 (6565.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3241	334.0 x 224.0 x 8.0		Laptop

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G	BACK, 2.00	U-NII- 7	WLAN, 10707- AAC	6565.0, 123	1.0

Hardware Setup

Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave - xxxx	Air -	EUmmWV4 - SN9641_F1-55GHz, 2024-10-10	DAE4 Sn1584, 2024-06-19

Scan Type	5G Scan	
Grid Extents [mm]	50.0 x 50.0	
Grid Steps [lambda]	0.044700090935831036 x 0.044700090935831036	
Sensor Surface [mm]	2.0	
MAIA	Y	
Measurement Results		
Scan Type	5G Scan	
Date	2024-12-13, 08:58	
Avg. Area [cm ²]	4.00	
psPDn+ [W/m²]	2.51	
psPDtot+ [W/m ²]	4.83	
psPDmod+ [W/m²]	5.96	
E _{max} [V/m]	74.5	
Power Drift [dB]	0.04	





Figure C40: iPD testing results for the A3241 at 6565 MHz Core 1



ANNEX D

THREAD TECHNOLOGY DUTY FACTOR CORRECTION